# SKM 800GA125D



SEMITRANS<sup>TM</sup> 3

# Ultrafast IGBT Modules

#### Features

- Homogeneous Si
- NPT-IGBT
- V<sub>CE(sat)</sub> with positive temperature coefficient
- High short circuit capability, self limiting to 6 x I<sub>C</sub>

## **Typical Applications**

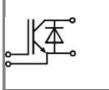
- Resonant inverters up to 100 kHz
- Inductive heating
- Electronic welders at fsw > 20 kHz

### Remarks

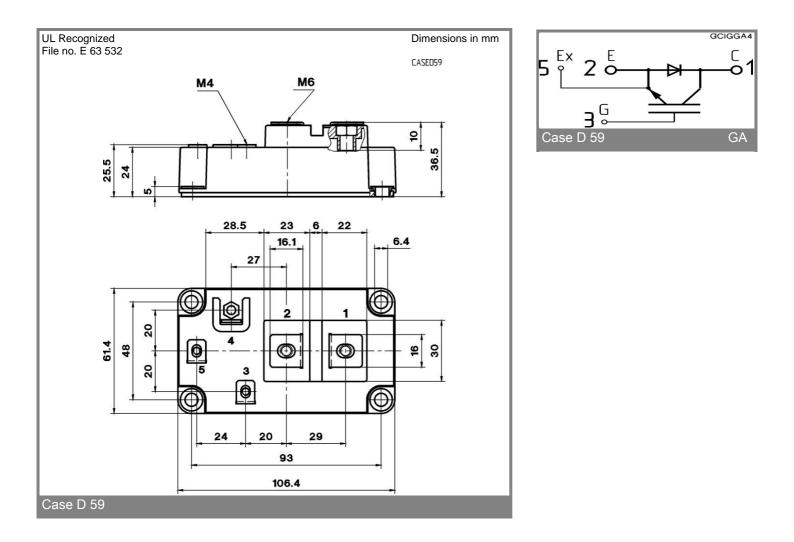
- I<sub>DC</sub> ≤ 500 A limited by terminals
  Take care of over-voltage caused
- Take care of over-voltage caused by stray inductances

Absolute Maximum Ratings		T <sub>case</sub> = 25°C, unless otherwise specified						
Symbol	Conditions	Values	Units					
IGBT								
V <sub>CES</sub>		1200	V					
I <sub>C</sub>	T <sub>c</sub> = 25 (80) °C	760 (530)	А					
ICRM	T <sub>c</sub> = 25 (80) °C, t <sub>p</sub> = 1 ms	1520 (1060)	А					
V <sub>GES</sub>		± 20	V					
T <sub>vj</sub> , (T <sub>stg</sub> )	$T_{OPERATION} \leq T_{stg}$	- 40 +150 (125)	°C					
V <sub>isol</sub>	AC, 1 min.	4000	V					
Inverse diode								
I <sub>F</sub>	T <sub>c</sub> = 25 (80) °C	720 (500)	А					
I <sub>FRM</sub>	T <sub>c</sub> = 25 (80) °C, t <sub>p</sub> = 1 ms	1520 (1060)	А					
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.; T <sub>i</sub> = 150 °C	5000	А					

<b>Characteristics</b> T <sub>case</sub> = 25°C, unless otherwise specifie						
Symbol	Conditions	min.	typ.	max.	Units	
IGBT						
V <sub>GE(th)</sub>	$V_{GE} = V_{CE}$ , $I_C = 24 \text{ mA}$	4,5	5,5	6,5	V	
ICES	V <sub>GE</sub> = 0, V <sub>CE</sub> = V <sub>CES</sub> , T <sub>j</sub> = 25 (125) °C		0,2	0,6	mA	
V <sub>CE(TO)</sub>	T <sub>j</sub> = 25 (125) °C		1,5 (1,7)	1,75 (1,3)	V	
r <sub>CE</sub>	V <sub>GE</sub> = 15 V, T <sub>j</sub> = 25 (125) °C		2,8 (3,8)	3,3 (5,4)	mΩ	
V <sub>CE(sat)</sub>	$I_{\rm C}$ = 600 A, $V_{\rm GE}$ = 15 V, chip level		3,2 (4)	3,75 (4,55)	V	
C <sub>ies</sub>	under following conditions		37		nF	
C <sub>oes</sub>	V <sub>GE</sub> = 0, V <sub>CE</sub> = 25 V, f = 1 MHz		5,6		nF	
C <sub>res</sub>			2,8		nF	
L <sub>CE</sub>				20	nH	
R <sub>CC'+EE'</sub>	res., terminal-chip T <sub>c</sub> = 25 (125) °C		0,18 (0,22)		mΩ	
t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V, I <sub>C</sub> = 600 A				ns	
t <sub>r</sub>	$R_{Gon} = R_{Goff} = \Omega, T_j = 125 \ ^{\circ}C$				ns	
t <sub>d(off)</sub>	V <sub>GE</sub> ± 15 V				ns	
t <sub>f</sub>					ns	
E <sub>on</sub> (E <sub>off</sub> )			52 (26)		mJ	
Inverse diode						
$V_F = V_{EC}$	I <sub>F</sub> = 600 A; V <sub>GE</sub> = 0 V; T <sub>j</sub> = 25 (125) °C		2,3 (2,1)	2,5 (2,3)	V	
V <sub>(TO)</sub>	$T_j = 25 (125) \ ^{\circ}C$		1,1 (0,9)	1,3 (1,05)	V	
r <sub>T</sub>	$T_{j} = 25 (125) \ ^{\circ}C$		2 (2)	2 (2,1)	mΩ	
I <sub>RRM</sub>	I <sub>F</sub> = 600 A; T <sub>j</sub> = 25 ( 125 ) °C				А	
Q <sub>rr</sub>	di/dt = A/µs				μC	
Err	$V_{GE} = 0 V$				mJ	
Thermal of	characteristics					
R <sub>th(j-c)</sub>	per IGBT			0,03	K/W	
R <sub>th(j-c)D</sub>	per Inverse Diode			0,07	K/W	
R <sub>th(c-s)</sub>	per module			0,038	K/W	
Mechanic	al data	•				
M <sub>s</sub>	to heatsink M6	3		5	Nm	
M <sub>t</sub>	to terminals (M6(M4)	2,5 (1,1)		5 (2)	Nm	
w				330	g	



GA



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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